^{83}Sr IT decay 1973Si16,1976Li27

History			
Type	Author	Citation	Literature Cutoff Date
Full Evaluation	E. A. Mccutchan	NDS 125, 201 (2015)	31-Dec-2014

Parent: ^{83}Sr: E=259.15 *9*; $J^{\pi}=1/2^-$; $T_{1/2}$=4.95 s *12*; %IT decay=100.0

^{83}Sr-%IT decay: since no β^+ decay from the isomeric 259-keV level has been observed, the evaluator assumes IT decay branching=100%.

1976Li27: Measured Eγ, Iγ, γ(t) using 2 coaxial Ge(Li) detectors and a low-energy Ge(Li) detector.

1973Si16: Measured Eγ, Iγ, γ(t) using two Ge(Li) detectors and a Ge(Li) x-ray detector, measured Ece, Ice using a cooled Si detector.

Additional information 1.

α: Additional information 2.

^{83}Sr Levels

E(level)†	J^{π}†	$T_{1/2}$†
0	$7/2^+$	32.41 h *3*
259.15 *9*	$1/2^-$	4.95 s *12*

† From the Adopted Levels.

γ(^{83}Sr)

Iγ normalization: from %IT=100.

E$_\gamma$†	I$_\gamma$‡	E$_i$(level)	J_i^{π}	E$_f$	J_f^{π}	Mult.	α	Comments
259.1 *1*	100	259.15	$1/2^-$	0	$7/2^+$	E3	0.1416 *20*	α(K)exp=0.16 (1973Si16) α(K)=0.1192 *17*; α(L)=0.0188 *3*; α(M)=0.00319 *5*; α(N)=0.000373 *6* Mult.: from α(K)exp.

† From 1976Li27.

‡ For absolute intensity per 100 decays, multiply by 0.876 *3*.

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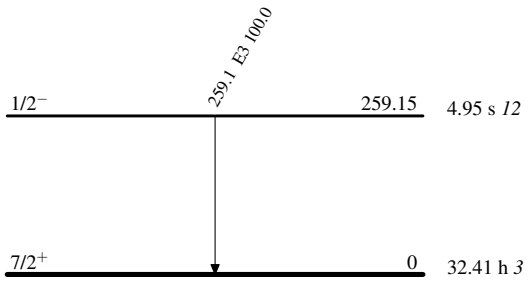
Decay Scheme

Intensities: $I_{(\gamma+ce)}$ per 100 parent decays
%IT=100.0



$^{83}_{38}Sr_{45}$